

Form PTO-1449

JUN 26 2000

PATENT & TRADEMARK OFFICE

U.S. DEPARTMENT OF COMMERCE

PATENT AND TRADEMARK OFFICE

CASE NO.

1717 P2

SERIAL NO.

09/512,734

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANT

Chen et al.

FILING DATE

February 18, 2000

GROUP

Not yet assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

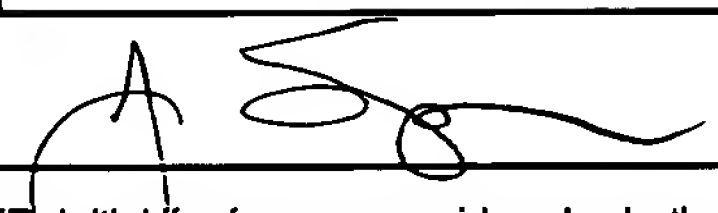
FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES	NO

OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)

			Simpson et al. "The Electrical Integrity of Copper Plated Wafers Using a Novel Plating Bath Chemistry"
			Abstract No. 727, The Electrochemical Chemical Society, October 17-22, 1999

EXAMINER




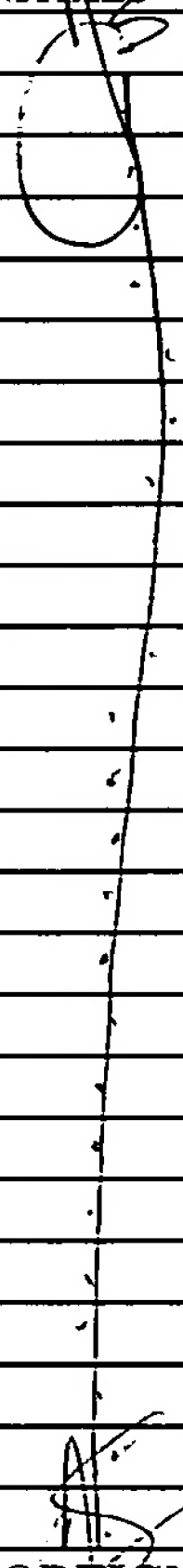
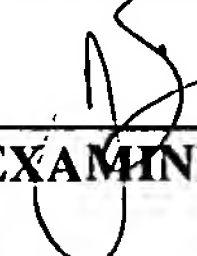
DATE CONSIDERED

70/16/01

*EXAMINER Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT (PTO-1449)				ATTY. DOCKET NO. 103864-1101		SERIAL NO. 09/512,734	
				APPLICANT Lasher et al.			
				FILING DATE February 24, 2000		GROUP 3721	



U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	3,139,713	1964	Merrill et al.	53	55	
	4,013,192	1977	Pillon	221	7	
	4,112,332	1978	Veith et al.	315	169	
	4,171,065	1979	Hurst	221	2	
	4,664,289	1987	Shimizu et al.	221	2	
	4,695,954	1987	Rose et al.	364	413	
	4,869,394	1989	Hurst	221	7	
	4,847,764	1989	Halvorson	364	413	
	4,953,745	1990	Rowlett, Jr.	221	5	
	5,208,762	1993	Charhut et al.	364	478	
	5,348,061	09/94	Riley et al.	221	2x	12/92
	4,674,259	06/87	Hills	53	501x	
	4,018,358	04/77	Johnson et al.	221	7	
	3,677,437	07/72	Haigler	221	7	
	3,193,196	07/65	Merrill et al.	53	501x	
	2,618,420	11/52	Levine	53	505	
	4,733,362	1988	Haraguchi	GO8H	5/00	
	4,870,799	10/89	Bergerioux et al	53	168	
	5,502,944	04/96	Kraft et al.	53	168	
	5,481,855	01/96	Yuyama	53	493	
	5,097,652	03/92	Inamura	53	168	
	5,884,806	03/23/99	Boyer et al.	221	75	12/02/96
	5,638,417	06/10/97	Boyer et al.	377	7	05/06/96
	5,671,262	09/23/97	Boyer et al.	377	11	05/06/96
	5,907,493	05/25/99	Boyer et al.	364	479.01	01/31/97
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
	WO98/09598		PCT/US/97/15472			
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
	"Baker Lockouts: Persistence Pays Off", Quality Bulletin, March 1993					
EXAMINER				DATE CONSIDERED		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

